TOSHIBA BIPOLAR DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TD62783AP,TD62783AFW,TD62784AP,TD62784AFW (Manufactured by Toshiba Malaysia)

8CH HIGH-VOLTAGE SOURCE DRIVER

The TD62783AP / AFW Series are comprised of eight source current Transistor Array.

These drivers are specifically designed for fluorescent display applications.

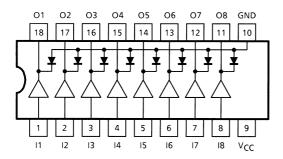
Applications include relay, hammer and lamp drivers.

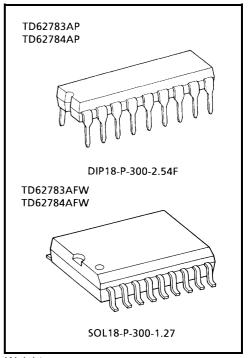
FEATURES

- High output voltage Type-AP, AFW : $V_{CC} = 50 \text{ V MIN}$. Type-F : $V_{CC} = 35 \text{ V MIN}$.
- Output current (single output) IOUT = -500 mA MIN.
- Output clamp diodes
- Single supply voltage
- Input compatible with various types of logic
- Package Type-AP : DIP-18 pin
- Package Type-AFW: SOL-18 pin

TYPE	DESIGNATION
TD62783AP / AFW	TTL, 5 V CMOS
TD62784AP / AFW	6~15 V PMOS, CMOS

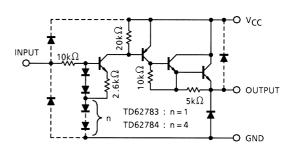
PIN CONNECTION (TOP VIEW)





Weight DIP18-P-300-2.54F : 1.478 g (Typ.) SOL18-P-300-1.27 : 0.48 g (Typ.)

SCHEMATICS (EACH DRIVER)



Note: The input and output parasitic diodes cannot be used as clamp diodes.

MAXIMUM RATINGS (Ta = 25°C)

CHARACTER	STIC	SYMBOL	RATING	UNIT	
Supply Voltage		V _{CC}	50	V	
Output Current		IOUT	-500	mA / ch	
Input Voltage		V _{IN} (Note 1)	15	V	
		V _{IN} (Note 2)	30	v	
Clamp Diode Reverse Voltage		V _R	50	V	
Clamp Diode Forward Cu	rrent	١ _F	500	mA	
Power Dissipation	AP	D-	1.47	W	
	AFW	P _D	0.92 / 1.31 (Note 3)	vv	
Operating Temperature		T _{opr}	-40~85	°C	
Storage Temperature		T _{stg}	-55~150	°C	

Note 1: Only TD62783AP / AFW

Note 2: Only TD62784AP / AFW

Note 3: On Glass Epoxy PCB (75 × 114 × 1.6 mm Cu 20%)

RECOMMENDED OPERATING CONDITIONS (Ta = -40~85°C)

	CHARACTERISTIC SYMBOL TEST		T CONDITION	MIN	TYP.	MAX	UNIT			
Supply V	Supply Voltage		V _{CC}	_		_	_	50	V	
Output Current			Ta = 85°C	Duty = 10% 8Circuits		_	-260	mA /		
				Duty = 50% 8Circuits		_	-59			
			IOUT	T _j = 120°C T _{pw} = 25ms	Duty = 10% 8Circuits		_	-180	ch	
		AFW			Duty = 50% 8Circuits	_	_	-38		
Input Voltage TD62783AP TD62784AP		/ AFW	V _{IN}	—		_	_	12	v	
		TD62784AP	/ AFW	۷IN		-	_	_	24	v
	Output On	TD62783AP	/ AFW	Variation	_		2.0	5.0	15	V
Input		TD62784AP	/ AFW	V _{IN (ON)}	_		4.5	12.0	30	
Voltage	Output Off	TD62783AP	/ AFW	V	_		0	-	0.8	
		TD62784AP	/ AFW	V _{IN (OFF)}	_		0	_	2.0	
	Clamp Diode Reverse AP		AP	V _R	_		_	_	50	v
Voltage AFW		٧R	_		_	_	35	v		
Clamp Diode Forward Current		١ _F	_			_	400	mA		
Power Dissipation AP		PD	Ta = 85°C		—	—	0.76	w		
		AFW	U '	Ta = 85°C (Note)		_	_	0.48	vv	

Note: On Glass Epoxy PCB (75 × 114 × 1.6 mm Cu 20%)

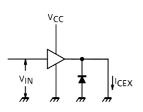
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
Output Leakage Current		ICEX	1	$V_{CC} = V_{CC MAX.} V_{IN} = 0.4 V$ Ta = 25°C		_	100	μA
Output Saturation Voltage		V _{CE (sat)}	2	V _{IN} = V _{IN (ON)} , I _{OUT} = −350 mA	-	_	2.0	V
				V _{IN} = V _{IN (ON)} , I _{OUT} = -225 mA		_	1.9	
				V _{IN} = V _{IN (ON)} , I _{OUT} = -100 mA		_	1.8	
	TD62783AP / AFW	- ^I in (on)	3	V _{IN} = 2.4 V		36	52	μA
				V _{IN} = 3.85 V	-	180	260	
Input Current	TD62784AP / AFW			V _{IN} = 5 V	-	92	130	
				V _{IN} = 12 V	_	790	1130	
	TD62783AP / AFW	Mariana	- 4	V _{CE} = 2.0 V	_	_	2.0	
Input Voltage	TD62784AP / AFW	VIN (ON)		I _{OUT} = −350 mA	_	_	4.5	v
Input Voltage	TD62783AP / AFW	M		I _{OUT} = -500 μA	0.8	_	_	V
	TD62784AP / AFW	V _{IN (OFF)}			2.0	-	_	
Supply Current		I _{CC (ON)}	3	$V_{IN} = V_{IN (ON)}, V_{CC} = 50 V$	-	_	2.5	mA / ch
Clamp Diode Reverse Current		I _R	5	V _R = 50 V	_	_	50	μA
Clamp Diode Forward Voltage		V _F	6	I _F = 350 mA	_	—	2.0	V
Turn-On Delay		t _{ON}	7	V _{CC} = V _{CC MAX.} R _L = 125 Ω	_	0.15	—	μs
Turn-Off Delay		tOFF		$C_{L} = 15 \text{ pF}, R_{L} = 88 \Omega (F)$	_	1.8	_	

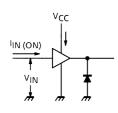
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TEST CIRCUIT

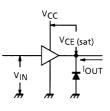
1. ICEX



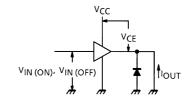
3. I_{IN (ON)}, I_{CC}



2. V_{CE (sat)}

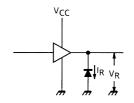


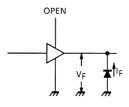
4. V_{IN (ON)}, V_{IN (OFF)}



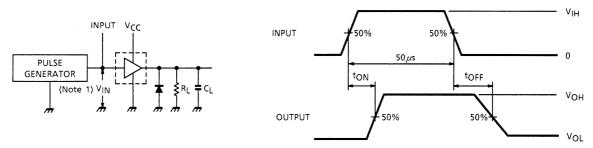
5. I_R

6. V_F





7. t_{ON}, t_{OFF}



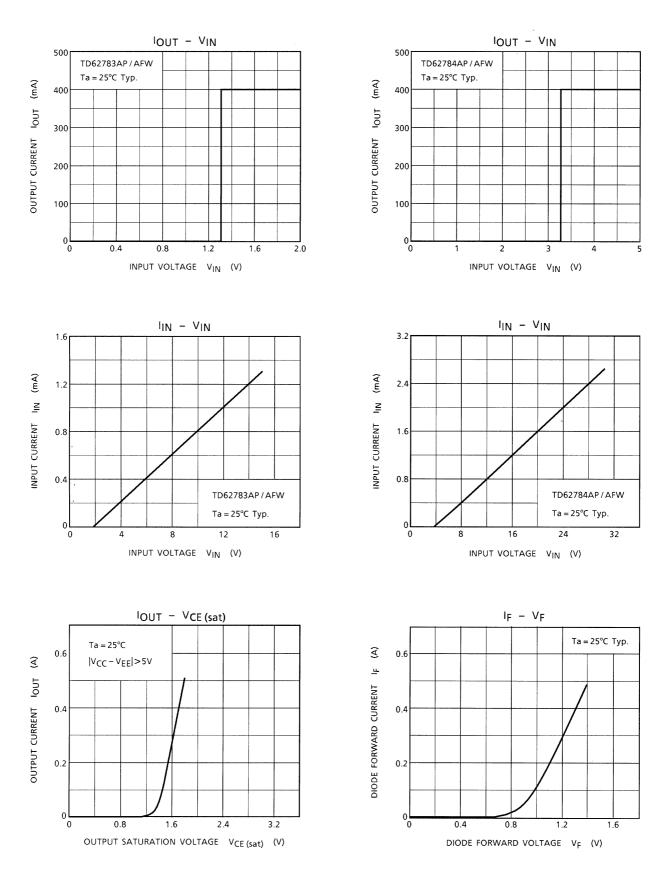
Note 1: Pulse width 50 μ s, duty cycle 10% Output impedance 50 Ω , t_r ≤ 5 ns, t_f ≤ 10 ns Note 2: C_L includes probe and jig capacitance

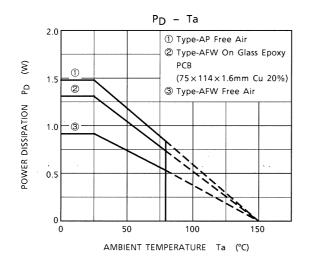
PRECAUTIONS for USING

This IC does not integrate protection circuits such as overcurrent and overvoltage protectors. Thus, if excess current or voltage is applied to the IC, the IC may be damaged. Please design the IC so that excess current or voltage will not be applied to the IC.

Utmost care is necessary in the design of the output line, V_{CC} and GND line since IC may be destroyed due to short-circuit between outputs, air contamination fault, or fault by improper grounding.

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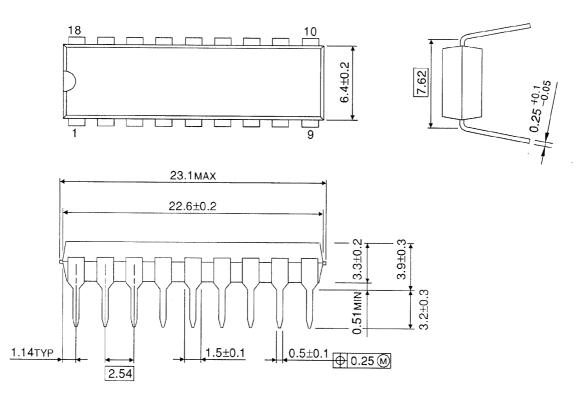


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PACKAGE DIMENSIONS

DIP18-P-300-2.54F

Unit: mm



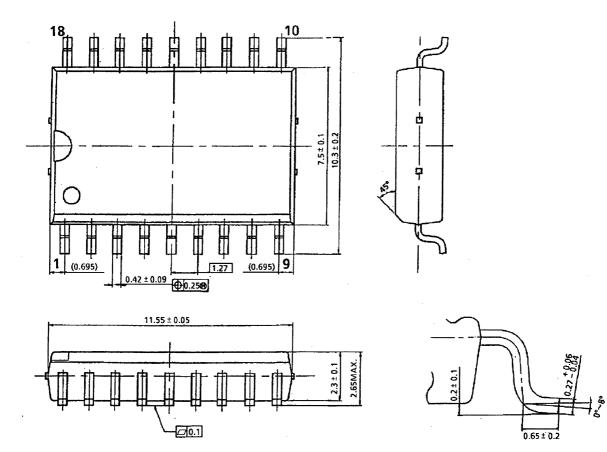
Weight: 1.478 g (Typ.)

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Unit: mm

PACKAGE DIMENSIONS

SOL18-P-300-1.27



Weight: 0.48 g (Typ.)

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